

<b>Notice of References Cited</b>	Application/Control No. 09/754,155	Applicant(s)/Patent Under Reexamination WEIL ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,711,585	03-2004	Copperman et al.	707/104.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO 00/51031	08-2000	US	Hendren et al.	G06F 17/30
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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